

**Experiment title:**Structures of the simple terminations of Fe₃O₄(111)**Experiment****number:**

SI-1364

Beamline: ID32	Date of experiment: from: 03/05/06 to: 09/05/06	Date of report: 30/08/06
Shifts: 21	Local contact(s): Dr Isabelle Joumard	<i>Received at ESRF:</i>

Names and affiliations of applicants (* indicates experimentalists):

* Professor Geoff Thornton

* Dr Gregory Cabailh

Department of Chemistry

University College London

20 Gordon Street

London WC1H 0AJ

UK

* Dr Xavier Torrelles

Institut de Ciencia de Materiales Barcelona

C.S.I.C

Campus de la U.A.B

E-08193 Bellaterra (Barcelona)

Spain

* Dr Rob Lindsay

Corrosion and Protection Centre

School of Materials

The University of Manchester

P.O. Box 88 Manchester M60 1QD

UK

* Dr Oier Bikondoa

ESRF

6 rue Jules Horowitz

F-38043 Grenoble cedex

France

Report:

In this experiment we attempted to carry out a quantitative structural determination of Fe₃O₄(111) using surface x-ray diffraction (SXRD) and scanning tunnelling microscopy (STM). *In situ* preparation was carried out in the UHV facilities located in the Surface Characterisation Laboratory (SCL) by repeated cycles of argon sputtering and annealing in up to 10⁻⁷ mbar O₂. Multiple domains were observed by LEED and STM. These were previously observed [1]. This is due to the anneal temperature being too high, which seemed to result from an inaccurate (underestimation) temperature reading. It is not possible to recover the sample to suppress the multi domain without polishing. Nevertheless we proceeded with the SXRD measurements to check the quality of the sample. The sample was transferred to the beamline under UHV, using a *Baby* chamber [2]. SXRD measurements were performed on beam line ID32, employing the diffractometer in EH1. X-ray experiments were performed at 17.7 keV. SXRD data were collected at room temperature using conventional rocking scans, in which the sample is rotated about its surface normal while scattered x-ray intensity is measured. For a given (*h.k*) these were performed at different *l*, enabling crystal truncation

rods (CTR's) to be compiled. 3 CTRs were measured, with a total of 136 reflections. In the CTRs, spurious peaks appear at some l =integer (arrows, see figure 1) that are due to the presence of multiple domains/crystallites. This probably arises from the high temperature anneal. As the possible terminations of $\text{Fe}_3\text{O}_4(111)$ give rise to similar CTRs (see figure 1), a full complete analysis requires a more extensive set of data.

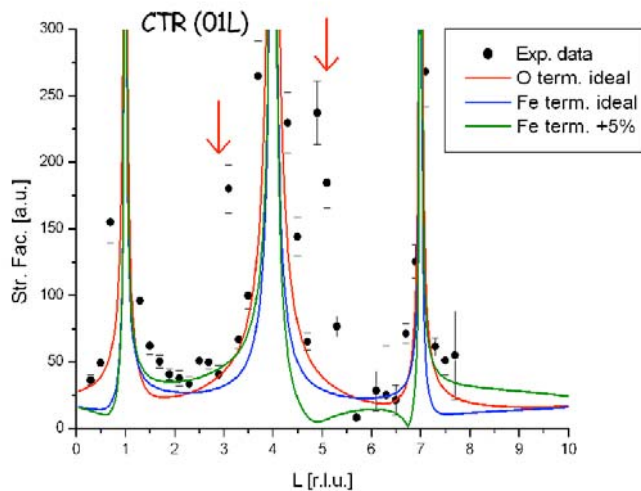


Figure 1. Crystal truncation rod (01L) for the $\text{Fe}_3\text{O}_4(111)$ surface. The curves correspond to the ideally O terminated (red) and Fe terminated (blue) surfaces, and a Fe-terminated surface with 5 % relaxation of the interlayer distance (green).

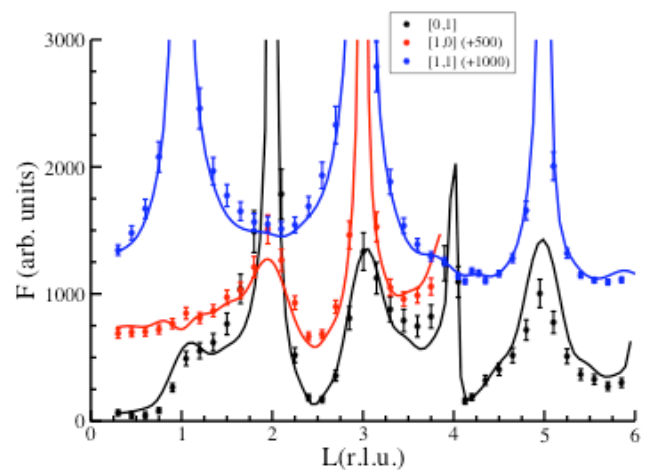


Figure 2. (01L), (10L) and (11L) crystal truncation rods for the $\text{TiO}_2(110)\text{-}1\times 1$ surface. Each CTR is represented in a given colour. Curves are offset for clarity. Continuous lines correspond to the obtained fit.

The $\text{TiO}_2(110)\text{-}1\times 1$ surface termination has also been measured to elucidate the discrepancies existing between recent experimental analysis on the same surface obtained with LEED [3], MEIS [4] and early X-ray diffraction measurements [5]. A rather large data set was measured involving 15 non-equivalent CTR's containing more than 700 reflections. This large data set was required to determine the modulus and directions of the atomic relaxations of the topmost surface atoms. The results obtained from the analysis of the XRD data coincide with those obtained by LEED and Ion scattering (MEIS). The controversy regarding the results obtained from different methods on this system is consequently resolved.

References:

- [1] R.A. Fellows et al., Surf. Sci. 445, 11 (2000)
- [2] www.esrf.fr/UsersAndScience/Experiments/SurfaceScience/ID32/SurfaceLab/
- [3] R. Lindsay et al., Phys. Rev. Lett. 94, 1 (2005)
- [4] G.S. Parkinson et al., Phys. Rev. B 73, 245409 (2006)
- [5] G. Charlton et al., Phys. Rev. Lett. 78, 495 (1997)